Supporting Information (SI)

Fabrication, characterization and water wetting behavior of mesoscale 1D/2D periodic structured silica-zirconia sol-gel thin films

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Figure S1: (a) AFM image with height profile (HP) of 1st imprinted gel film.



Figure S2: *AFM images of the film at different applied pressure after the* 2^{nd} *imprinting showing the change of fidelity of the 2D pattern. The applied pressure (Pa) for each case is embedded at the bottom.*



Figure S3: (*a*, *b*, *c*) *AFM* images and their corresponding HP (a1, b1, c1) for 1^{st} imprint, (a2, b2, c2) for 2^{nd} imprint and (a3, b3, c3) for the both direction of the films. The HP of the films changes depending upon the curing temperature (as described in each case).



Figure S4: (*a*, *b*, *c*) *AFM* images for the well ordered 2D pattern at an optimum applied pressure ($\sim 1.198Pa$) and (*d*) and (*e*) correspond to the HP of the films which shows nearly same value of HP a square pillar-like pattern.



Figure S5: *Nanoindentation plot (load vs. depth) of the gel film (the measurement has been done after 45 min of film deposition)*



Figure S6: *FESEM images of (a) 1D and (b) 2D patterned films cured at 500°C. The images at relatively higher magnification are shown in the insets and the presence of different elements in 1D film is evidenced from the FESEM-EDS curve (inset ii) of the film.*



Figure S7: *XRD reflections of the films cured at different temperatures (insets i and ii are the AFM images of the film cured at 300° and 500°C, respectively).*